

Knowledge Base Article

Product Group: Microlog Analyzer

Product: Microlog series

Version: N/A

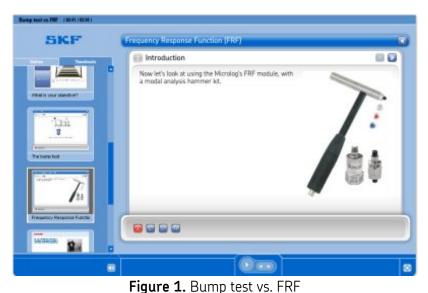
Abstract

This document contains a link to a brief video presentation that explains the difference between a simple "bump" test and more comprehensive modal analysis. The presentation comprises of 8 slides with an audio soundtrack, but it is also suitable for silent viewing.

Overview

Click on the following link to be directed to a video presentation as shown in Figure 1:





The link will direct the user to the **SKF @ptitude Exchange** website. Registration is required in order to view this presentation. There is no cost to register.